



RADIO TEST REPORT

Test Report No. : 28IE0224-HO

Applicant : Sharp Corporation, Communication Systems Group.
Type of Equipment : Cellular Phone
Model No. : WX-T825
FCC ID : APYHRO00074
Test regulation : FCC Part 15 Subpart C 2008
Section 15.207, Section 15.247
Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test: June 25 and July 3, 2008

Tested by:

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Takahiro Hatakeda
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NVLAP[®]

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*As for the range of Accreditation in NVLAP, you may refer to the WEB address, <http://uljapan.co.jp/emc/nvlap.htm>

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MF060b (09.01.08)

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SECTION 1: Customer information

Company Name : Sharp Corporation, Communication Systems Group.
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Japan
Telephone Number : +81-82-420-1837
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Contact Person : Tetsuya Maekawa

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Cellular Phone
Model No. : WX-T825
Serial No. : 004401/11/135070/4 (Antenna Terminal conducted tests)
004401/11/135069/6 (Conducted Emission and Radiated Emission tests)
Rating : AC 120V/60Hz, DC4.0V
Receipt Date of Sample : June 24, 2008
Country of Mass-production : Japan
Condition of EUT : Engineering prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: WX-T825 (referred to as the EUT in this report) is the Cellular Phone.

Clock frequency(ies) in the system : 26MHz
[Bluetooth (Ver. 2.0 without EDR function)]
Equipment Type : Transceiver
Frequency of Operation : 2402-2480MHz
Bandwidth & Channel Spacing : 1MHz & 1MHz / CH
Modulation : FHSS
Power Supply (inner) : DC 2.75V
Antenna Type : Internal Antenna
Antenna Gain : 0dBi
Operating temperature range : -10 to +55 deg. C.

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2008, final revised on May 19, 2008

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.247 Operation within the bands 902-928MHz,
2400-2483.5MHz, and 5725-5850MHz

FCC 15.31 (e)

This EUT provides stable voltage(DC2.75V) constantly to RF Module regardless of input voltage and Radiated Emission test was performed with the New Battery. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.2 Procedures and results

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst Margin	Results			
1	Conducted emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements	FCC: Section 15.207	-	N/A	[Tx] QP 17.4dB, 4.64540MHz, N AV 12.9dB, 4.64540MHz, N [Rx] QP 17.9dB, 4.22600MHz, L AV 12.9dB, 4.22600MHz, L	Complied			
		IC: RSS-Gen 7.2.2	IC: RSS-Gen 7.2.2							
2	Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)	Conducted	N/A	See data.	Complied			
		IC: -	IC: RSS-210 A8.1 (b)							
3	20dB Bandwidth	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)	Conducted	N/A		See data.	Complied		
		IC: -	IC: RSS-210 A8.1 (a)							
4	Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)(iii)	Conducted	N/A			See data.	Complied	
		IC: -	IC: RSS-210 A8.1 (d)							
5	Dwell time	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)(iii)	Conducted	N/A				See data.	Complied
		IC: -	IC: RSS-210 A8.1 (d)							
6	Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(b)(1)	Conducted	N/A	See data.				Complied
		IC: RSS-Gen 4.8	IC: RSS-210 A8.4 (2)							
7	Band Edge Compliance	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(d)	Conducted	N/A		See data.			Complied
		IC: -	IC: RSS-210 A8.5							
8	Spurious Emission	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(d)	Conducted/ Radiated	N/A			See data.		Complied
		IC: RSS-Gen 4.9 RSS-Gen 4.10	IC: RSS-210 A8.5 RSS-Gen 7.2.1 and 7.2.3							

Note: UL Japan, Inc.'s EMI Work Procedures No. QPM05 and QPM15.

*These tests were performed without any deviations from test procedure except for additions or exclusions.

* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

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3.3 Addition to standards

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied Band Width	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	Conducted	N/A	N/A	N/A

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission	Radiated emission (10m*)			Radiated emission (3m*)			Radiated emission (3m*)	
		150kHz-30MHz	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	1GHz-18GHz
No.1 semi-anechoic chamber (±)	3.7dB	3.1dB	4.4dB	4.2dB	3.2dB	3.8dB	3.9dB	5.9dB	6.1dB
No.2 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.4dB	4.0dB	5.9dB	6.1dB
No.3 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.6dB	4.0dB	5.9dB	6.1dB
No.4 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	3.9dB	3.9dB	5.9dB	6.1dB

*10m/3m = Measurement distance

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

Other test except Conducted Emission and Spurious Emission (Radiated)

The measurement uncertainty for this test is 3.0dB.

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3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Test instruments and Data of EMI

Refer to APPENDIX 1 to 3.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Test	Mode	Tested frequency
Conducted Emission	Bluetooth(BT), Transmitting (Tx), Payload: PRBS9 -DH5	2402MHz 2441MHz 2480MHz
	Bluetooth(BT), Receiving (Rx)	2441MHz
Carrier Frequency Separation	Bluetooth(BT), Transmitting (Tx) (Hopping ON)/Inquiry, Payload: PRBS9 -DH5	2402MHz 2441MHz 2480MHz
20dB Bandwidth	Bluetooth(BT), Transmitting (Tx) (Hopping Off)/Inquiry, Payload: PRBS9 -DH5	2402MHz 2441MHz 2480MHz
Number of Hopping Frequency	Bluetooth(BT), Transmitting (Tx) (Hopping ON)/Inquiry, Payload: PRBS9 -DH5	-
Dwell time	Bluetooth(BT), Transmitting (Tx) (Hopping ON)/Inquiry -DH1 -DH3 -DH5	-
Maximum Peak Output Power	Bluetooth(BT), Transmitting (Tx) (Hopping Off)/Inquiry, Payload: PRBS9 -DH5	2402MHz 2441MHz 2480MHz
Spurious Emission (Conducted/Radiated)	Bluetooth(BT), Transmitting (Tx), Payload: PRBS9 -DH5	2402MHz 2441MHz 2480MHz
	Bluetooth(BT), Receiving (Rx)	2441MHz
Band Edge Compliance (Conducted)	Bluetooth(BT), Transmitting (Tx), (Hopping ON)/(Hopping Off) Payload: PRBS9 -DH5	2402MHz 2480MHz
99% Occupied Bandwidth	Bluetooth(BT), Transmitting (Tx), (Hopping ON)/(Hopping Off)/Inquiry Payload: PRBS9 -DH5	2402MHz 2441MHz 2480MHz

*As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload (except Dwell time test)

Remarks: Test was not performed at AFH mode, because the decrease of number of channel (min: 20ch) at AFH mode does not influence on the output power and bandwidth of the EUT.
However, the limit level 125mW of AFH mode was used for the test.

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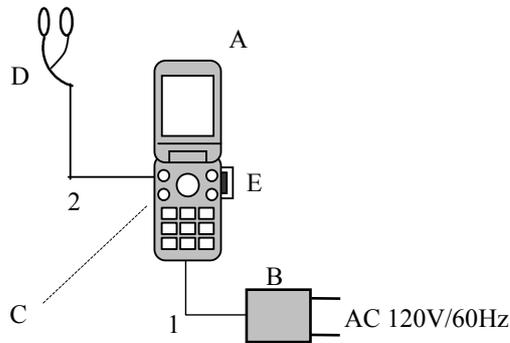
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4.2 Configuration and peripherals



* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Cellular Phone	WX-T825	004401/11/135070/4 *1) 004401/11/135069/6 *2)	SHARP	EUT
B	AC Charger	XN-1QC73	PDA	HOSIDEN	EUT
C	Rechargeable Lithium-ion Battery	XN-1BT81	REA	SANYO	-
D	Stereo Handsfree	RPHOHA018AF	01	HOSIDEN	-
E	microSD Memory Card	SDSDQ-128	01	SanDisk	-

*1) Used for Antenna Terminal conducted tests

*2) Used for Conducted Emission and Radiated Emission tests

List of cables used

No.	Name	Length (m)	Shield	
			Cable	Connector
1	AC Charger Cable	1.5	Unshielded	Unshielded
2	Stereo Handsfree Cable	1.7	Unshielded	Unshielded

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SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 80cm above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

AC cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber or a Measurement Room.

The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

Detector : quasi-peak and average detector (IF BW 9 kHz)
Measurement range : 0.15-30MHz
Test data : APPENDIX 2
Test result : Pass

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SECTION 6: Spurious Emission

[Conducted]

Test Procedure

The Out of Band Emission was measured with a spectrum analyzer connected to the antenna port.
The following spectrum analyzer setting was used:

- RBW: 100kHz
- VBW: 300kHz
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2
Test result : Pass

[Radiated]

Test Procedure

EUT was placed on urethane platform of nominal size, 0.5m by 1.0m, raised 80cm above the conducting ground plane.
The Radiated Electric Field Strength intensity has been measured in a Semi Anechoic Chamber with a ground plane and at a distance of 3m(Below 10GHz) and 1m(above 10GHz).

The height of the measuring varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

The result also satisfied with the general limits specified in section FCC 15.209(a) / RSS-210 2.7 (IC).

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Spectrum Analyzer
Detector	QP: BW 120kHz	PK: RBW:1MHz/VBW: 1MHz
IF Bandwidth		AV: RBW:1MHz/VBW:10Hz or RBW:1MHz/VBW:270Hz *1)

*1) Used for the band edge of the carrier and the harmonics that can be measured. The VBW is based on the inverse of the duty cycle (see page 40).

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

Test data : APPENDIX 2
Test result : Pass

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SECTION 7: Bandwidth

20dB Bandwidth

Test Procedure

The bandwidth was measured with a spectrum analyzer connected to the antenna port.
The following spectrum analyzer setting was used:

- Span: 3MHz
- RBW: 30kHz
- VBW: 100kHz
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2

Test result : Pass

99% Occupied Bandwidth

Test Procedure

The bandwidth was measured with a spectrum analyzer connected to the antenna port.
The following spectrum analyzer setting was used:

- Span: Enough width to display 20dB Bandwidth
- RBW: 1 to 3% of Span
- VBW: Three times of RBW
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2

Test result : Pass

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SECTION 8: Maximum Peak Output Power

Test Procedure

The Maximum Peak Output Power was measured with a power meter (tested bandwidth: 50MHz) connected to the antenna port.

Test data : APPENDIX 2
Test result : Pass

SECTION 9: Carrier Frequency Separation

Test Procedure

The carrier frequency separation was measured with a spectrum analyzer connected to the antenna port. The following spectrum analyzer setting was used:

- Span: 3MHz and 5MHz
- RBW: 100kHz
- VBW: 300kHz
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2
Test result : Pass

SECTION 10: Number of Hopping Frequency

Test Procedure

The Number of Hopping Frequency was measured with a spectrum analyzer connected to the antenna port.
The following spectrum analyzer setting was used:

- Span: 30MHz
- RBW: 300kHz
- VBW: 1MHz
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2
Test result : Pass

SECTION 11: Dwell time

Test Procedure

The Dwell time was measured with a spectrum analyzer connected to the antenna port.
The following spectrum analyzer setting was used:

- Span: Zero Span
- RBW: 1MHz
- VBW: 3MHz
- Sweep: as necessary to capture the entire dwell time per hopping channel
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2
Test result : Pass

APPENDIX 1: Photographs of test setup

Conducted Emission

This page has been submitted for a separate exhibit.

Spurious Emission (Radiated)

This page has been submitted for a separate exhibit.

Worst Case Position (Horizontal: Y-axis/ Vertical:Z-axis)

This page has been submitted for a separate exhibit.

APPENDIX 2: Data of EMI test

Conducted Emission
Tx, Ch:Low (DH5)

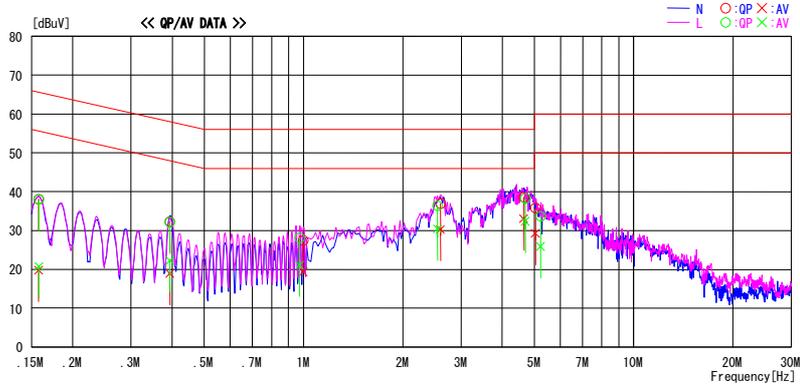
DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No. 3 Semi Anechoic Chamber
Date : 2008/06/25

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : WX-T825
Serial No. : 004401/11/135069/6
Report No. : 28IE0224-HO
Power : AC120V / 60Hz
Temp./Humi. : 25deg. C. / 62%
Engineer : Takahiro Hatake

Mode / Remarks : BT, Tx 2402MHz, DH5

LIMIT : FCC15.207 QP
FCC15.207 AV



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15750	37.8	19.5	0.3	38.1	19.8	65.6	55.6	27.5	35.8	N	
0.39376	31.9	18.6	0.4	32.3	19.0	58.0	48.0	25.7	29.0	N	
0.99776	27.0	18.9	0.5	27.5	19.4	56.0	46.0	28.5	26.6	N	
2.59876	36.2	29.6	0.7	36.9	30.3	56.0	46.0	19.1	15.7	N	
4.64540	37.3	31.8	1.3	38.6	33.1	56.0	46.0	17.4	12.9	N	
5.04000	34.5	28.0	1.3	35.8	29.3	60.0	50.0	24.2	20.7	N	
0.15780	37.8	20.4	0.3	38.1	20.7	65.6	55.6	27.5	34.9	L	
0.39376	31.8	21.9	0.4	32.2	22.3	58.0	48.0	25.8	25.7	L	
0.97108	27.6	20.6	0.5	28.1	21.1	56.0	46.0	27.9	24.9	L	
2.54600	35.7	29.7	0.7	36.4	30.4	56.0	46.0	19.6	15.6	L	
4.69780	37.0	31.1	1.3	38.3	32.4	56.0	46.0	17.7	13.6	L	
5.22140	32.2	24.5	1.4	33.6	25.9	60.0	50.0	26.4	24.1	L	

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT[dBuV]=READING[dBuV]+C. F[dB] (LISN+CABLE LOSS)
Except for the above table: adequate margin data below the limits.

*The test result is round off to one or two decimal places, so some differences might be observed.

Conducted Emission
Tx, Ch:Mid (DH5)

DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.3 Semi Anechoic Chamber
 Date : 2008/06/25

Company : Sharp Corporation
 Kind of EUT : Cellular Phone
 Model No. : WX-T825
 Serial No. : 004401/11/135069/6

Report No. : 28IE0224-HO
 Power : AC120V / 60Hz
 Temp./Humi. : 25deg. C. / 62%
 Engineer : Takahiro Hatakeda

Mode / Remarks : BT, Tx 2441MHz, DH5

LIMIT : FCC15. 207 QP
 FCC15. 207 AV

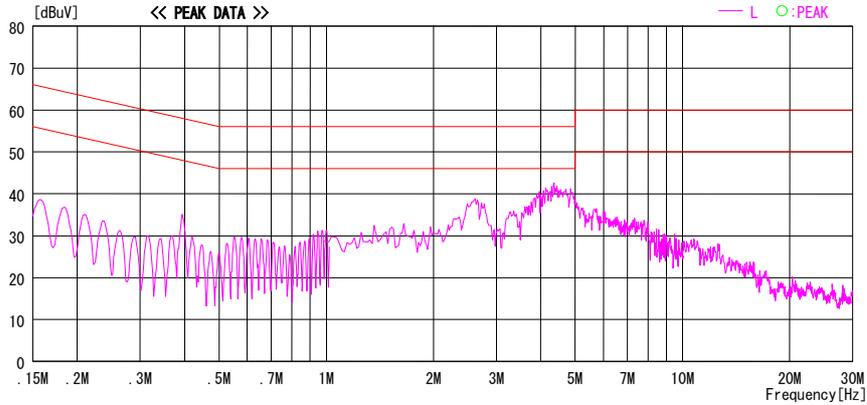
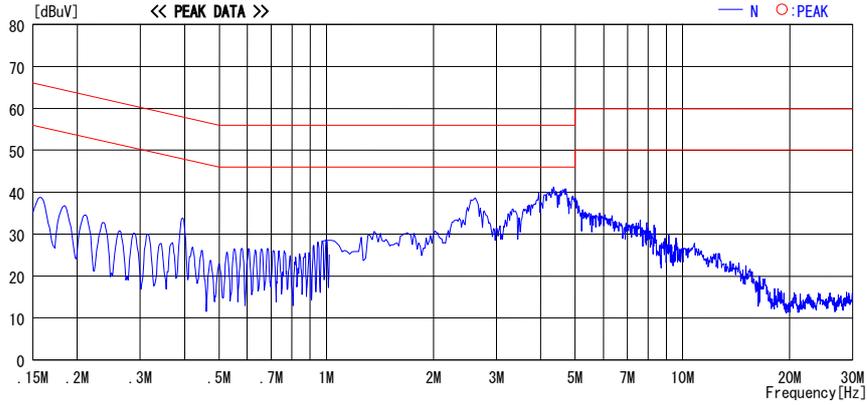


CHART: WITH FACTOR, Peak hold data. CALCURATION: RESULT[dBuV]=READING[dBuV]+C. F[dB] (LISN+CABLE LOSS)
 Except for the above table: adequate margin data below the limits.

Conducted Emission
Tx, Ch:High (DH5)

DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.3 Semi Anechoic Chamber
 Date : 2008/06/25

Company : Sharp Corporation
 Kind of EUT : Cellular Phone
 Model No. : WX-T825
 Serial No. : 004401/11/135069/6

Report No. : 28IE0224-HO
 Power : AC120V / 60Hz
 Temp./Humi. : 25deg. C. / 62%
 Engineer : Takahiro Hatakeda

Mode / Remarks : BT, Tx 2480MHz, DH5

LIMIT : FCC15. 207 QP
 FCC15. 207 AV

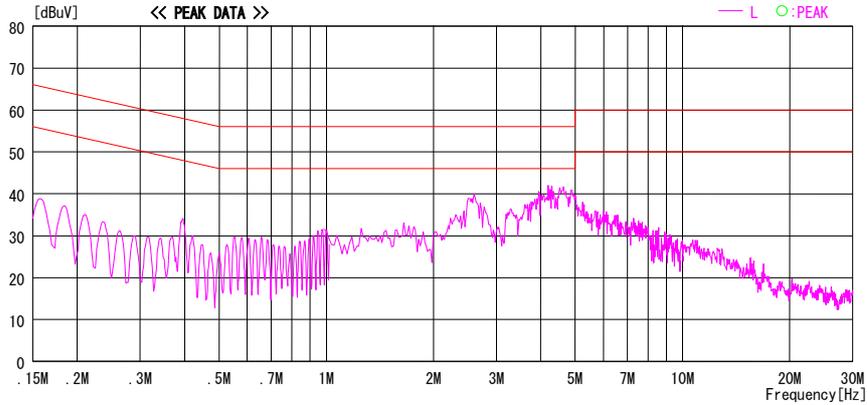
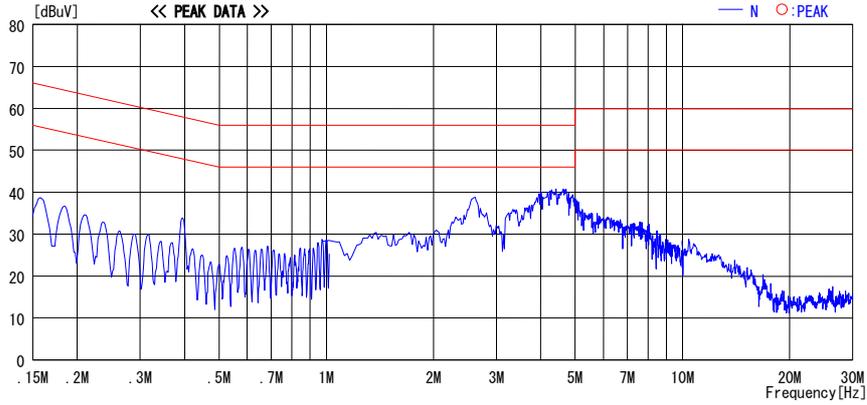


CHART: WITH FACTOR, Peak hold data. CALCURATION: RESULT[dBuV]=READING[dBuV]+C. F[dB] (LISN+CABLE LOSS)
 Except for the above table: adequate margin data below the limits.

Conducted Emission
Rx, Ch:Mid

DATA OF CONDUCTED EMISSION TEST

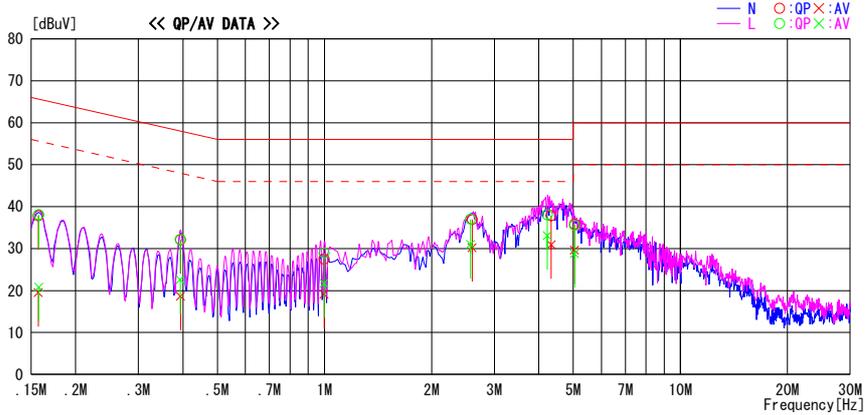
UL Japan, Inc. Head Office EMC Lab. No.3 Semi Anechoic Chamber
Date : 2008/06/25

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : WX-T825
Serial No. : 004401/11/135069/6

Report No. : 281E0224-HO
Power : AC120V / 60Hz
Temp./Humi. : 25deg. C. / 62%
Engineer : Takahiro Hatakeda

Mode / Remarks : BT, Rx 2441MHz

LIMIT : FCC15. 207 QP
FCC15. 207 AV



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15696	37.5	19.2	0.3	37.8	19.5	65.6	55.6	27.8	36.1	N	
0.15750	37.8	20.5	0.3	38.1	20.8	65.6	55.6	27.5	34.8	L	
0.39300	31.8	22.2	0.4	32.2	22.6	58.0	48.0	25.8	25.4	L	
0.39400	31.7	18.2	0.4	32.1	18.6	58.0	48.0	25.9	29.4	N	
0.99796	27.0	18.6	0.5	27.5	19.1	56.0	46.0	28.5	26.9	N	
0.99744	28.4	21.2	0.5	28.9	21.7	56.0	46.0	27.1	24.3	L	
2.57240	36.3	30.3	0.7	37.0	31.0	56.0	46.0	19.0	15.0	L	
2.59840	36.2	29.5	0.7	36.9	30.2	56.0	46.0	19.1	15.8	N	
4.22600	36.9	31.9	1.2	38.1	33.1	56.0	46.0	17.9	12.9	L	
4.33200	36.6	29.7	1.2	37.8	30.9	56.0	46.0	18.2	15.1	N	
5.03990	34.3	27.5	1.3	35.6	28.8	60.0	50.0	24.4	21.2	L	
5.03836	34.5	28.3	1.3	35.8	29.6	60.0	50.0	24.2	20.4	N	

CHART: WITH FACTOR, Peak hold data. CALCURATION: RESULT[dBuV]=READING[dBuV]+C.F[dB] (LISN+CABLE LOSS)
Except for the above table: adequate margin data below the limits.

*The test result is round off to one or two decimal places, so some differences might be observed.

Carrier Frequency Separation
(DH5 / Inquiry)

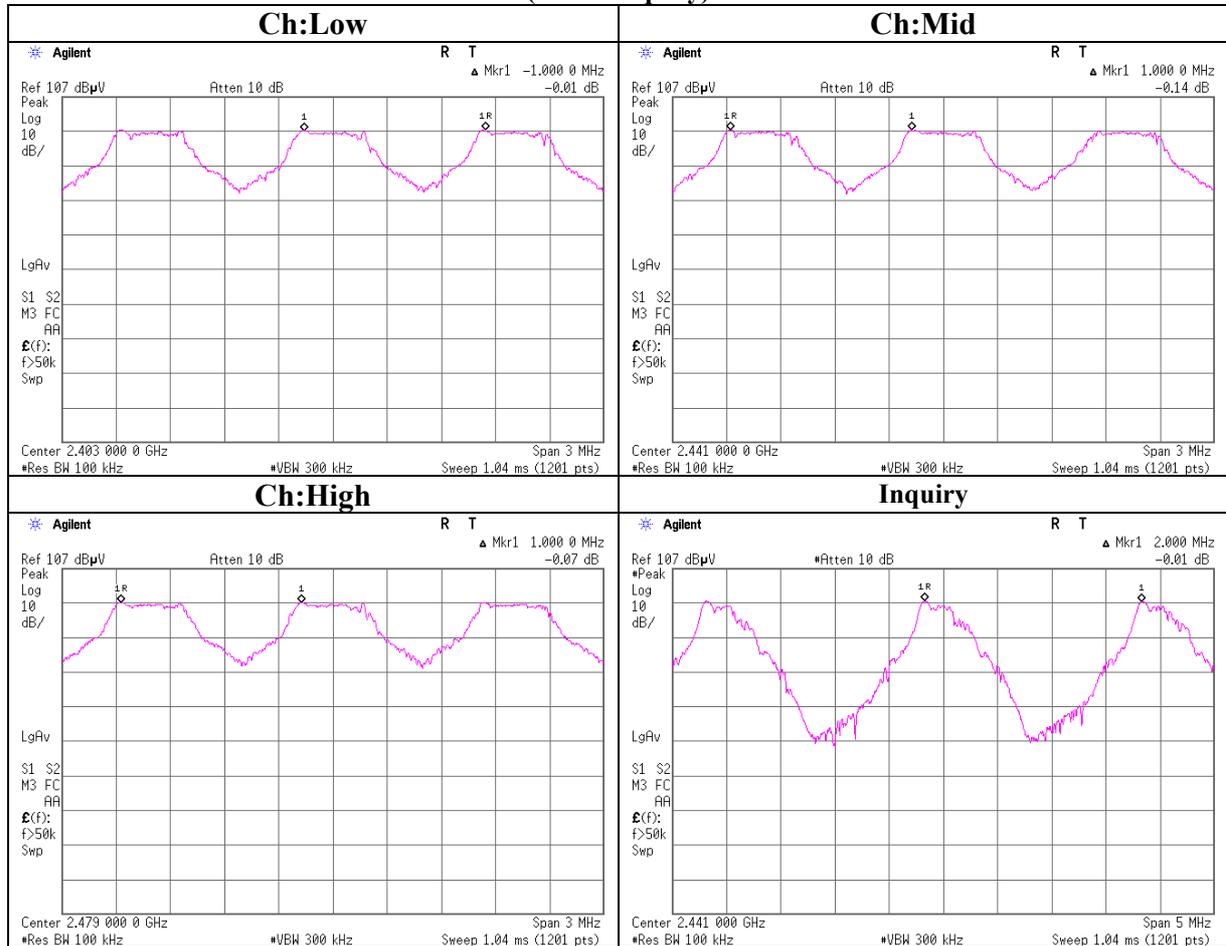
UL Japan, Inc.
 Head Office EMC Lab. No.3 shielded room

Company : Sharp Corporation
 Equipment : Cellular Phone
 Model No. : WX-T825
 Serial No. : 004401/11/135070/4
 Power : AC120V/60Hz
 MODE : BT DH5, Tx(Hopping on)/Inquiry

Test Report No. : 28IE0224-HO
 REGULATION : FCC15.247(a)(1)/RSS-210A8.1(b)
 TEST DISTANCE : -
 DATE : 07/3/2008
 TEMPERATURE : 24 deg.C.
 HUMIDITY : 58 %
 ENGINEER : Tomotaka Sasagawa

Ch	Freq. [MHz]	Channel separation [MHz]	Limit
Low	2402.0	1.000	0.640 [MHz] (two-thirds of 20dB Bandwidth 0.960 [MHz]) or 25[kHz] (whichever is grater)
Mid	2441.0	1.000	0.645 [MHz] (two-thirds of 20dB Bandwidth 0.968 [MHz]) or 25[kHz] (whichever is grater)
High	2480.0	1.000	0.648 [MHz] (two-thirds of 20dB Bandwidth 0.973 [MHz]) or 25[kHz] (whichever is grater)
Inquiry	2441.0	2.000	0.555 [MHz] (two-thirds of 20dB Bandwidth 0.833 [MHz]) or 25[kHz] (whichever is grater)

Carrier Frequency Separation
(DH5 / Inquiry)



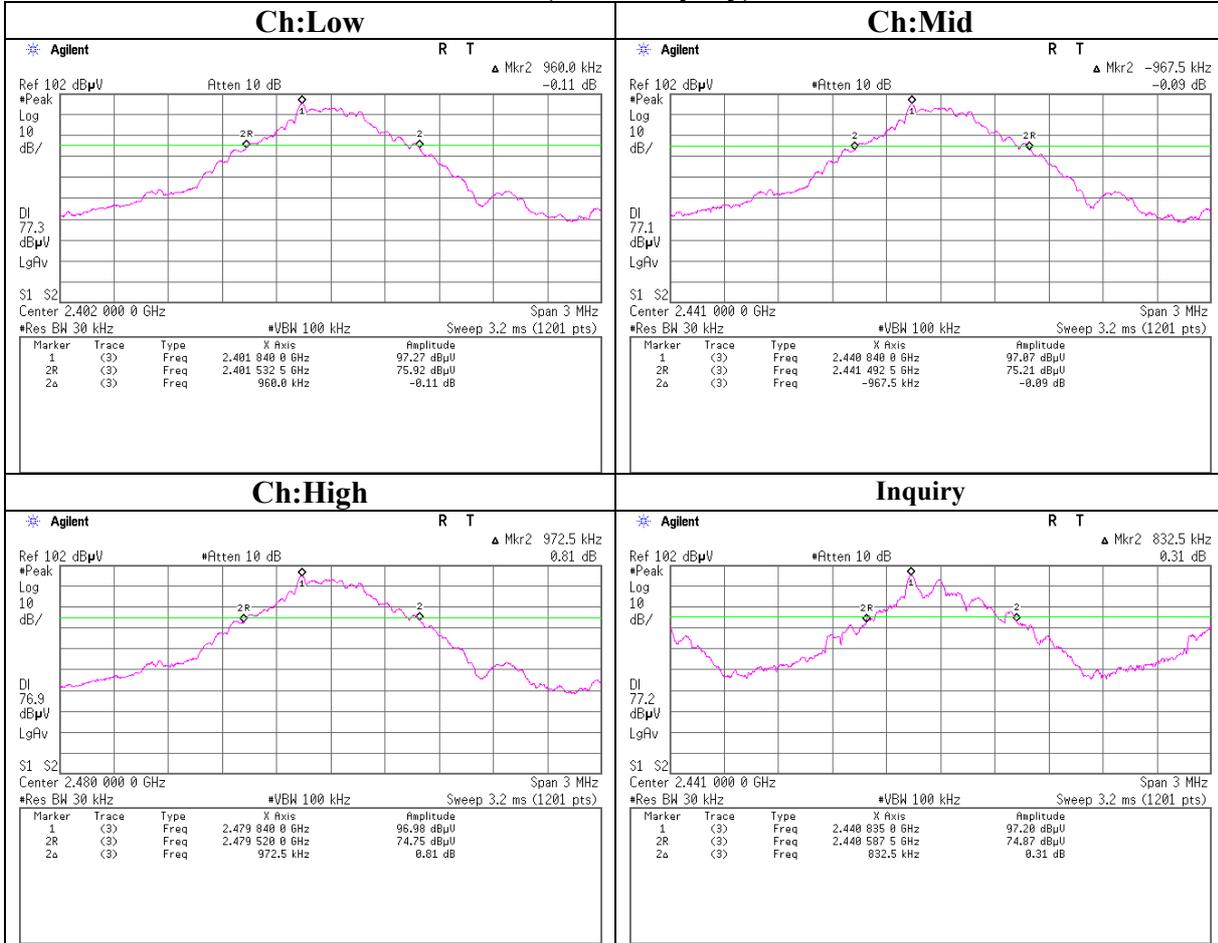
20dB Bandwidth
(DH5 / Inquiry)

Company : Sharp Corporation
Equipment : Cellular Phone
Model No. : WX-T825
Serial No. : 004401/11/135070/4
Power : AC120V/60Hz
Mode : BT DH5, Tx (Hopping off) /Inquiry

UL Japan, Inc.
Head Office EMC Lab. No.3 shielded room
Test Report No. : 28IE0224-HO
Regulation : FCC15.247(a)(1)/RSS-210A8.1(a)
Test distance : -
Date : 07/3/2008
Temperature : 24 deg.C.
Humidity : 58 %
Engineer : Tomotaka Sasagawa

Ch	Freq. [MHz]	20dB Bandwidth [MHz]	Limit [MHz]
Low	2402.0	0.960	-
Mid	2441.0	0.968	-
High	2480.0	0.973	-
Inquiry	2441.0	0.833	-

**20dB Bandwidth
(DH5 / Inquiry)**



Number of Hopping Frequency
(DH5 / Inquiry)

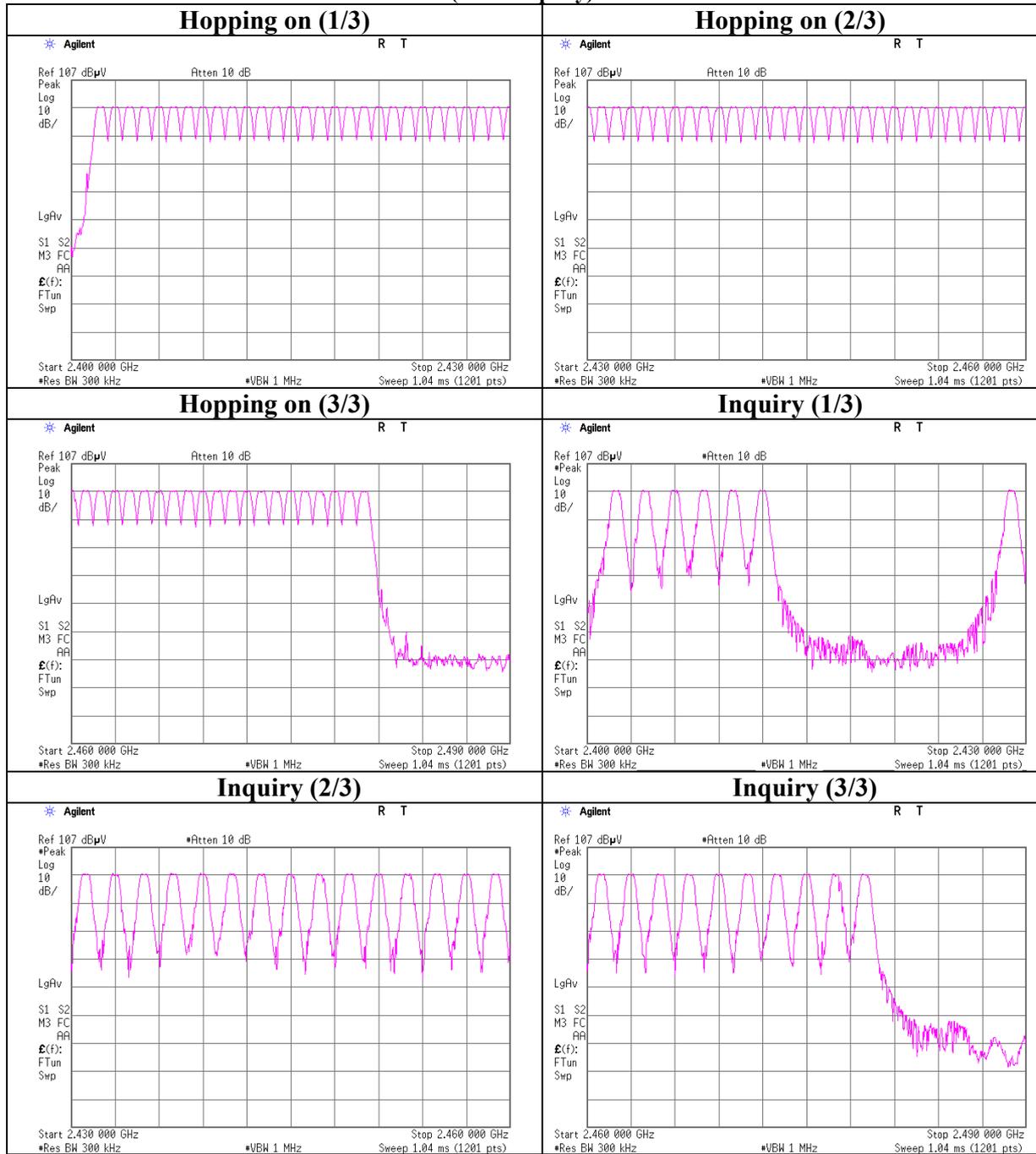
Company : Sharp Corporation
Equipment : Cellular Phone
Model No. : WX-T825
Serial No. : 004401/11/135070/4
Power : AC120V/60Hz
Mode : BT DH5, Tx (Hopping on)/Inquiry

UL Japan, Inc.
Head Office EMC Lab. No.3 shielded room
Test Report No. : 28IE0223-HO
Regulation : FCC15.247(a)(1)(iii)/RSS-210A8.1(d)
Test distance : -
Date : 07/3/2008
Temperature : 24 deg.C.
Humidity : 58 %
Engineer : Tomotaka Sasagawa

Mode	Number of channel	Limit
	[number]	[number]
DH5	79	≥ 15

Mode	Number of channel	Limit
	[number]	[number]
Inquiry	32	≥ 15

**Number of Hopping Frequency
(DH5/Inquiry)**



Dwell time

<p>Company : Sharp Corporation Equipment : Cellular Phone Model No. : WX-T825 Serial No. : 004401/11/135070/4 Power : AC120V/60Hz Mode : BT, Tx (Hopping on)/Inquiry</p>	<p>UL Japan, Inc. Head Office EMC Lab. No.3 shielded room Test Report No. : 28IE0224-HO Regulation : FCC15.247(a)(1)(iii)/RSS-210A8.1(d) Test distance : - Date : 07/3/2008 Temperature : 24 deg.C. Humidity : 58 % Engineer : Tomotaka Sasagawa</p>
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Mode	Number of transmission in a 31.6(79 Hopping x 0.4) / 12.8(32 Hopping x 0.4)second period	Length of transmission time [msec]	Result [msec]	Limit [msec]
DH1	50.6 times / 5 sec. x 31.6 sec. = 320 times	0.413	132	400
DH3	27.4 times / 5 sec. x 31.6 sec. = 174 times	1.682	293	400
DH5	19.0 times / 5 sec. x 31.6 sec. = 121 times	2.938	355	400
Inquiry	100.0 times / 1 sec. x 12.8 sec. = 1280 times	0.137	175	400

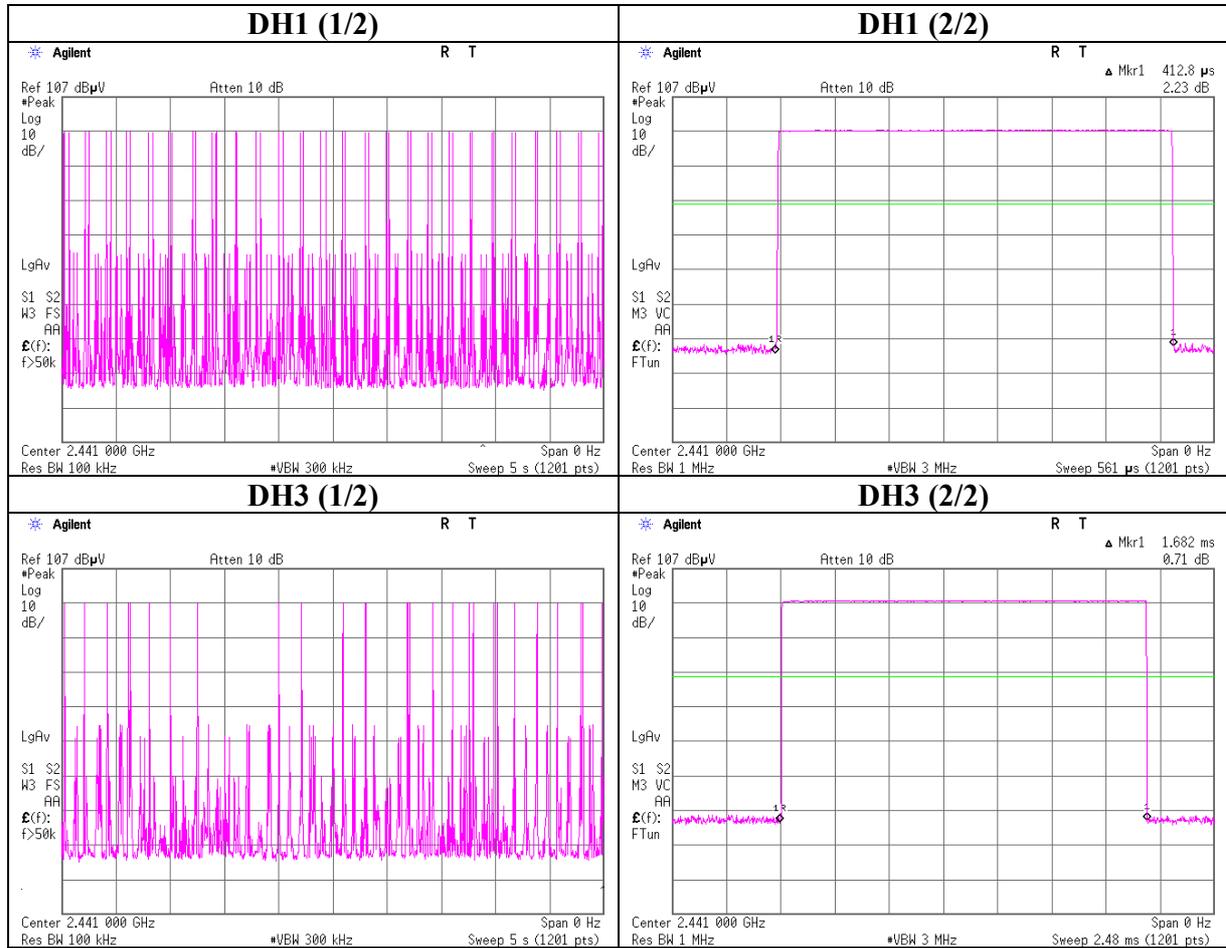
* Average data of 5 tests.(except Inquiry)

*DH1 / 1:50, 2:51, 3:51, 4:51, 5:50 = 50.6 times

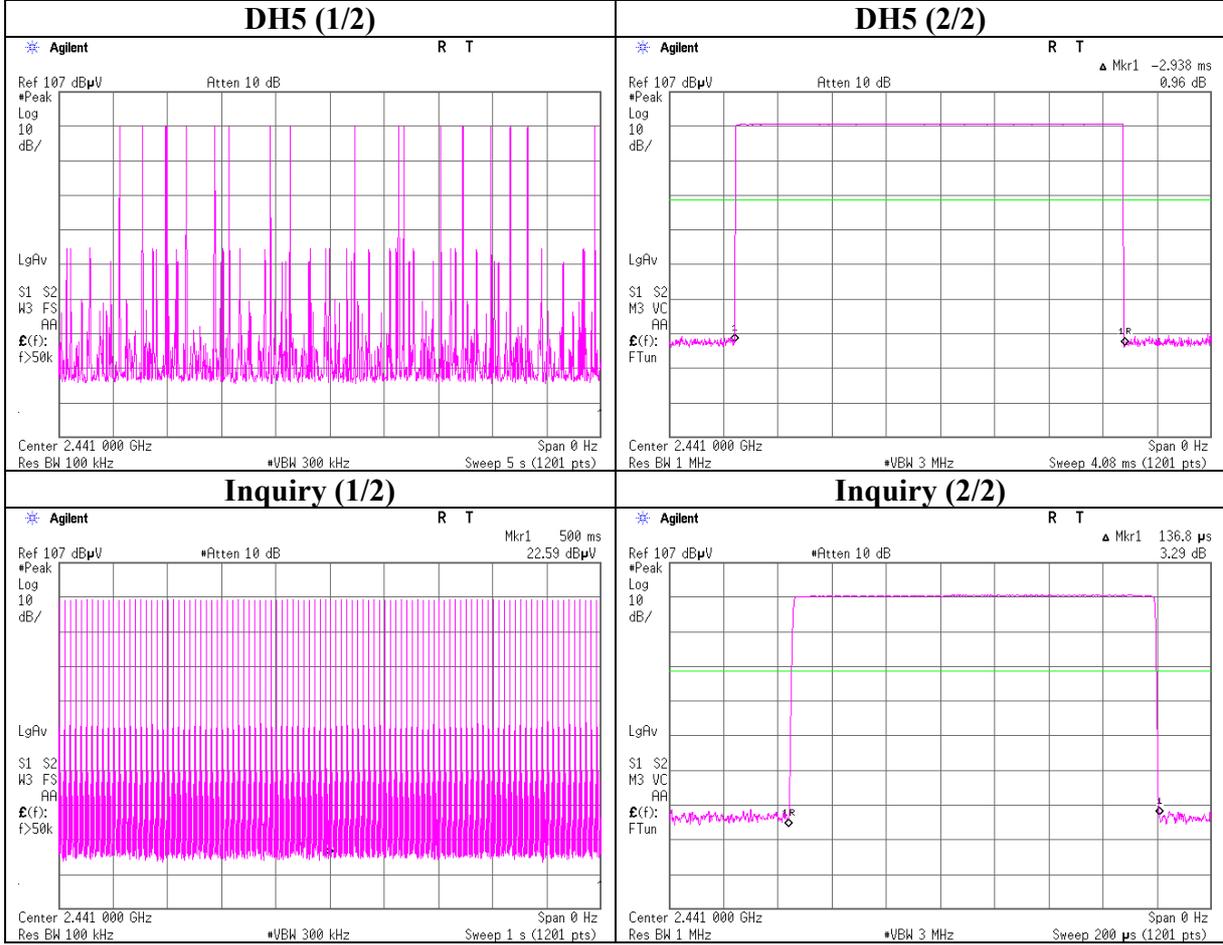
*DH3 / 1:27, 2:28, 3:28, 4:27, 5:27 = 27.4 times

*DH5 / 1:18, 2:20, 3:20, 4:19, 5:18 = 19.0 times

Dwell time



Dwell time



**Maximum Peak Output Power
(DH5 / Inquiry)**

UL Japan, Inc.

Head Office EMC Lab. No.3 shielded room

Company : Sharp Corporation

Equipment : Cellular Phone

Model No. : WX-T825

Serial No. : 004401/11/135070/4

Power : AC120V/60Hz

Mode : BT DH5, Tx(Hopping Off)/Inquiry

Test Report No. : 28IE0224-HO

Regulation : FCC15.247(b)(1)/RSS-210A8.4(2)

Test distance : -

Date : 07/3/2008

Temperature : 24 deg.C.

Humidity : 58 %

Engineer : Tomotaka Sasagawa

Ch	Freq. [MHz]	P/M Reading [dBm]	Cable Loss [dB]	Atten. [dB]	Result		Limit		Margin [dB]
					[dBm]	[mW]	[dBm]	[mW]	
Low	2402.0	-8.08	0.15	10.09	2.16	1.64	20.97	125	18.81
Mid	2441.0	-8.02	0.15	10.09	2.22	1.67	20.97	125	18.75
High	2480.0	-8.17	0.15	10.09	2.07	1.61	20.97	125	18.90
Inquiry	2441.0	-8.14	0.15	10.09	2.10	1.62	20.97	125	18.87

Sample Calculation:

Result = Reading + Cable Loss (supplied by customer)+ Attenuator

* In the above table, factor 0.0dB represents no use of Atten. and/or Filter.

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

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Radiated Spurious Emission (below 1GHz)
Tx, Ch:Low (DH5)

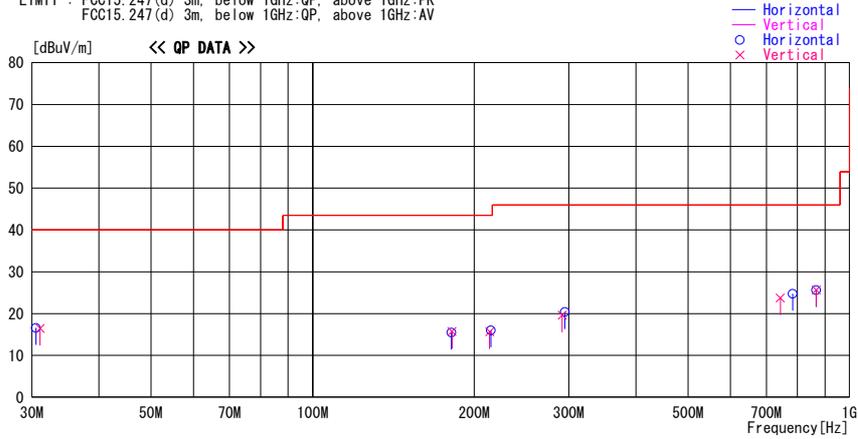
SATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.3 Semi Anechoic Chamber
Date : 2008/07/03

Company : Sharp Corporation Report No. : 281E0224-HO
Kind of EUT : Cellular Phone Power : AC120V / 60Hz
Model No. : WX-T825 Temp./Humi. : 24deg. C. / 58%
Serial No. : 004401/11/135069/6 Engineer : Tomotaka Sasagawa

Mode / Remarks : BT, Tx 2402MHz, DH5 Worst-axis(Hor:Y, Ver:Z)

LIMIT : FCC15.247(d) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.247(d) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna		Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]
			Factor [dB/m]	Loss& Gain [dB]						
30.540	23.0	QP	18.6	-25.0	16.6	215	300	Hori.	40.0	23.5
31.080	23.1	QP	18.3	-25.0	16.4	50	100	Vert.	40.0	23.6
181.200	22.3	QP	16.4	-23.2	15.5	268	300	Hori.	43.5	28.0
181.740	22.5	QP	16.4	-23.2	15.7	61	100	Vert.	43.5	27.8
213.601	22.1	QP	16.3	-22.8	15.6	203	100	Vert.	43.5	27.9
214.681	22.5	QP	16.3	-22.8	16.0	297	300	Hori.	43.5	27.5
294.870	22.8	QP	19.7	-22.1	20.4	5	300	Hori.	46.0	25.7
291.532	22.3	QP	19.5	-22.2	19.6	0	100	Vert.	46.0	26.4
783.680	22.3	QP	21.5	-19.0	24.8	0	100	Hori.	46.0	21.2
742.976	22.4	QP	20.7	-19.4	23.7	0	100	Vert.	46.0	22.3
866.682	22.4	QP	21.4	-18.1	25.7	0	100	Hori.	46.0	20.4
867.080	22.4	QP	21.4	-18.1	25.7	0	100	Vert.	46.0	20.3

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Spurious Emission (below 1GHz)
Tx, Ch:Mid (DH5)

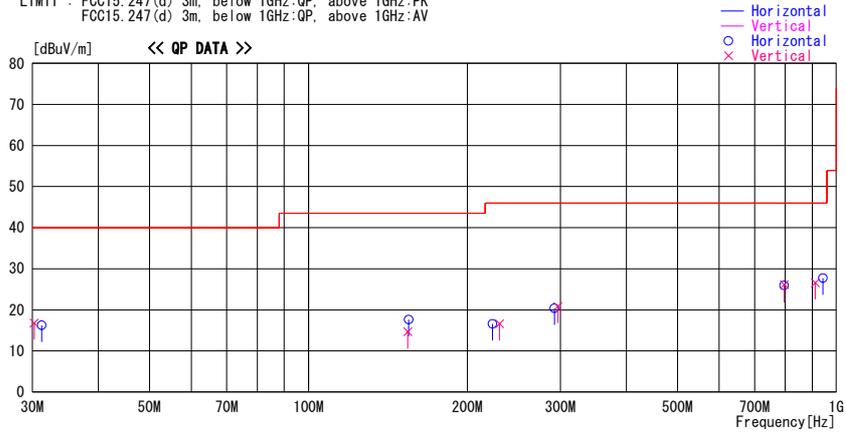
SATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.3 Semi Anechoic Chamber
Date : 2008/07/03

Company : Sharp Corporation Report No. : 281E0224-HO
Kind of EUT : Cellular Phone Power : AC120V / 60Hz
Model No. : WX-T825 Temp./Humi. : 24deg. C. / 58%
Serial No. : 004401/11/135069/6 Engineer : Tomotaka Sasagawa

Mode / Remarks : BT, Tx 2441MHz, DH5 Worst-axis(Hor:Y, Ver:Z)

LIMIT : FCC15.247(d) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.247(d) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna		Level	Angle	Height	Polar.	Limit	Margin
			Factor	Loss& Gain						
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]
30.245	23.0	QP	18.8	-25.0	16.8	0	100	Vert.	40.0	23.2
31.224	23.1	QP	18.2	-25.0	16.3	0	100	Hori.	40.0	23.7
154.852	25.8	QP	15.1	-23.3	17.6	310	100	Hori.	43.5	25.9
154.200	22.9	QP	15.1	-23.3	14.7	0	100	Vert.	43.5	28.8
223.051	23.0	QP	16.3	-22.7	16.6	0	100	Hori.	46.0	29.4
230.223	22.9	QP	16.4	-22.7	16.6	0	100	Vert.	46.0	29.4
297.030	23.1	QP	19.8	-22.1	20.8	0	100	Vert.	46.0	25.2
292.421	23.0	QP	19.5	-22.1	20.4	0	100	Hori.	46.0	25.6
796.440	23.1	QP	21.8	-18.8	26.1	0	100	Vert.	46.0	19.9
796.000	23.0	QP	21.8	-18.8	26.0	0	100	Hori.	46.0	20.0
943.211	23.1	QP	22.1	-17.5	27.7	0	100	Hori.	46.0	18.3
912.511	22.8	QP	21.5	-17.7	26.6	0	100	Vert.	46.0	19.4

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The test result is round off to one or two decimal places, so some differences might be observed.

Radiated Spurious Emission (below 1GHz)
Tx, Ch:High (DH5)

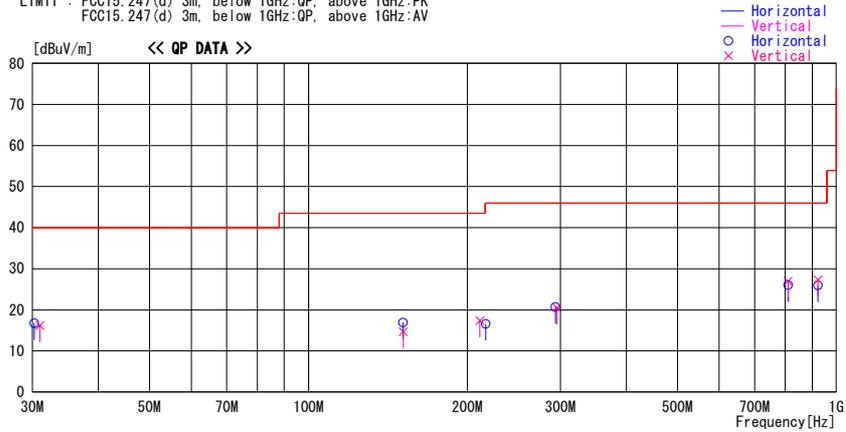
SATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.3 Semi Anechoic Chamber
Date : 2008/07/03

Company : Sharp Corporation Report No. : 281E0224-HO
Kind of EUT : Cellular Phone Power : AC120V / 60Hz
Model No. : WX-T825 Temp./Humi. : 24deg. C. / 58%
Serial No. : 004401/11/135069/6 Engineer : Tomotaka Sasagawa

Mode / Remarks : BT, Tx 2480MHz, DH5 Worst-axis(Hor:Y, Ver:Z)

LIMIT : FCC15.247(d) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.247(d) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna		Level	Angle	Height	Polar.	Limit	Margin
			Factor	Gain						
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]
30.270	22.9	QP	18.8	-25.0	16.7	81	300	Hori.	40.0	23.3
30.988	22.8	QP	18.4	-25.0	16.2	0	100	Vert.	40.0	23.8
150.960	25.4	QP	14.9	-23.4	16.9	5	100	Hori.	43.5	26.6
151.221	23.1	QP	15.0	-23.4	14.7	0	100	Vert.	43.5	28.8
216.571	23.1	QP	16.3	-22.8	16.6	204	300	Hori.	46.0	29.4
211.221	23.9	QP	16.3	-22.8	17.4	98	100	Vert.	43.5	26.1
295.441	22.9	QP	19.7	-22.1	20.5	0	100	Vert.	46.0	25.5
293.422	23.2	QP	19.6	-22.1	20.7	358	300	Hori.	46.0	25.3
809.609	23.8	QP	21.8	-18.6	27.0	0	100	Vert.	46.0	19.0
809.609	22.9	QP	21.8	-18.6	26.1	0	100	Hori.	46.0	19.9
923.221	23.2	QP	21.7	-17.6	27.3	0	100	Vert.	46.0	18.7
922.655	21.9	QP	21.7	-17.6	26.0	0	100	Hori.	46.0	20.0

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Spurious Emission (below 1GHz)
Rx, Ch:Mid

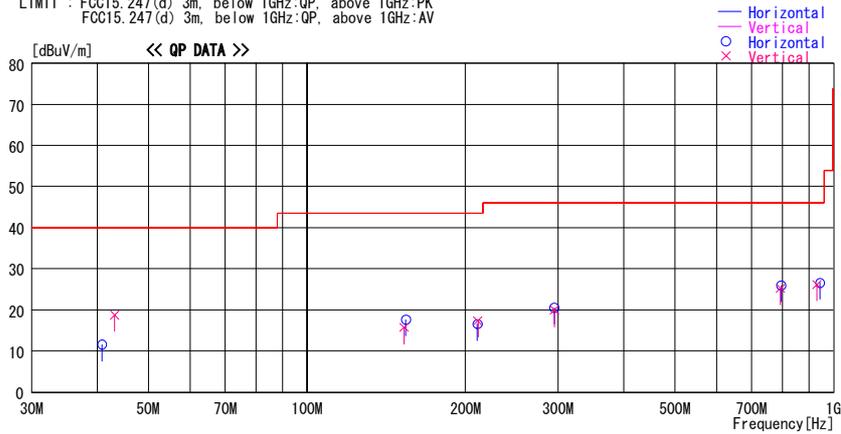
SATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.3 Semi Anechoic Chamber
Date : 2008/07/03

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : WX-T825
Serial No. : 004401/11/135069/6
Report No. : 28IE0224-HO
Power : AC120V / 60Hz
Temp./Humi. : 24deg. C. / 58%
Engineer : Tomotaka Sasagawa

Mode / Remarks : BT, Rx 2441MHz, Worst-axis(Hor:Y, Ver:Z)

LIMIT : FCC15.247(d) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.247(d) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna		Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]
			Factor [dB/m]	Loss Gain [dB]						
40.800	23.2	QP	13.2	-24.8	11.6	0	100	Hori.	40.0	28.4
43.170	31.2	QP	12.3	-24.8	18.7	0	100	Vert.	40.0	21.3
152.901	24.1	QP	15.0	-23.4	15.7	175	100	Vert.	43.5	27.8
154.200	25.8	QP	15.1	-23.3	17.6	11	100	Hori.	43.5	25.9
211.306	23.9	QP	16.3	-22.8	17.4	97	100	Vert.	43.5	26.1
210.901	23.1	QP	16.3	-22.8	16.6	0	100	Hori.	43.5	26.9
294.870	22.9	QP	19.7	-22.1	20.5	0	100	Hori.	46.0	25.5
295.410	22.3	QP	19.7	-22.1	19.9	0	100	Vert.	46.0	26.1
796.309	23.0	QP	21.8	-18.8	26.0	0	100	Hori.	46.0	20.0
794.350	22.3	QP	21.7	-18.8	25.2	0	100	Vert.	46.0	20.8
929.560	22.0	QP	21.8	-17.6	26.2	0	100	Vert.	46.0	19.8
943.224	22.0	QP	22.1	-17.5	26.6	0	100	Hori.	46.0	19.4

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Spurious Emission (above 1GHz)
Tx, Ch:Low (DH5)

UL Japan, Inc.
Head Office EMC Lab. No.3Semi Anechoic Chamber

Company : Sharp Corporation
Equipment : Cellular Phone
Model No. : WX-T825
Sample No. : 004401/11/135069/6
Power : AC 120V/60Hz
Mode : BT Tx DH5 2402MHz
Remarks : Hor Y , Ver Z-axis

REPORT NO : 28IE0224-HO
REGULATION : FCC15.247(d)/RSS-210A8.5
TEST DISTANCE : 3/1m
DATE : 06/25/2008
TEMPERATURE : 25deg.C
HUMIDITY : 62%
ENGINEER : Takahiro Hatakeda

PK DETECT (RBW: 1MHz, VBW: 1MHz)

No.	FREQ [MHz]	S/A READING		ANT Factor [dB/m]	AMP GAIN [dB]	CABLE LOSS [dB]	Hi-Pass Filter [dB]	RESULT		Limit PK [dBuV/m]	MARGIN	
		HOR	VER					HOR	VER		HOR	VER
Test distance 3meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss												
1	2390.0	42.2	42.2	26.7	32.8	2.6	0.0	38.7	38.7	73.9	35.2	35.2
2	2400.0	65.0	64.7	26.7	32.8	2.6	0.0	61.5	61.2	73.9	12.4	12.7
3	4804.0	44.4	45.8	31.2	30.7	4.1	0.8	49.8	51.2	73.9	24.1	22.7
4	7206.0	42.9	42.3	35.6	31.4	4.6	0.7	52.4	51.8	73.9	21.5	22.1
5	9608.0	42.2	41.6	38.3	32.0	5.4	1.1	55.0	54.4	73.9	18.9	19.5
Test distance 1.0meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss - Dfac												
6	12010.0	-	-	-	-	-	-	-	-	-	-	-
7	14412.0	-	-	-	-	-	-	-	-	-	-	-
8	16814.0	-	-	-	-	-	-	-	-	-	-	-
9	19216.0	-	-	-	-	-	-	-	-	-	-	-
10	21618.0	-	-	-	-	-	-	-	-	-	-	-
11	24020.0	46.0	46.4	38.4	31.2	7.7	0.0	51.4	51.8	73.9	22.5	22.1

AV DETECT (RBW: 1MHz, VBW: 270Hz)

No.	FREQ [MHz]	S/A READING		ANT Factor [dB/m]	AMP GAIN [dB]	CABLE LOSS [dB]	Hi-Pass Filter [dB]	RESULT		Limit AV [dBuV/m]	MARGIN	
		HOR	VER					HOR	VER		HOR	VER
Test distance 3meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss												
1	2390.0	29.6	29.5	26.7	32.8	2.6	0.0	26.1	26.0	53.9	27.8	27.9
2	2400.0	40.8	40.6	26.7	32.8	2.6	0.0	37.3	37.1	53.9	16.6	16.8
3	4804.0	35.4	37.9	31.2	30.7	4.1	0.8	40.8	43.3	53.9	13.1	10.6
4	7206.0	29.4	29.3	35.6	31.4	4.6	0.7	38.9	38.8	53.9	15.0	15.1
5	9608.0	29.2	29.1	38.3	32.0	5.4	1.1	42.0	41.9	53.9	11.9	12.0
Test distance 1.0meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss - Dfac												
6	12010.0	-	-	-	-	-	-	-	-	-	-	-
7	14412.0	-	-	-	-	-	-	-	-	-	-	-
8	16814.0	-	-	-	-	-	-	-	-	-	-	-
9	19216.0	-	-	-	-	-	-	-	-	-	-	-
10	21618.0	-	-	-	-	-	-	-	-	-	-	-
11	24020.0	32.8	32.9	38.4	31.2	7.7	0.0	38.2	38.3	53.9	15.7	15.6

Test Distance 1.0m : Distance Factor(Dfac) = 20log(3/1) = 9.5dB

*Except for the above table : All other spurious emissions were less than 20dB for the limit.

*In the frequency over the 3rd harmonic, the noise from the EUT was not seen. The data above is its base noise.

*The test result is round off to one or two decimal places, so some differences might be observed.

*Hi-Pass Filter was not used for factor 0.0dB of the above table.

**Radiated Spurious Emission (above 1GHz)
Tx, Ch:Mid (DH5)**

UL Japan, Inc.
Head Office EMC Lab. No.3Semi Anechoic Chamber

Company : Sharp Corporation
Equipment : Cellular Phone
Model No. : WX-T825
Sample No. : 004401/11/135069/6
Power : AC 120V/60Hz
Mode : BT Tx DH5 2441MHz
Remarks : Hor Y , Ver Z-axis

REPORT NO : 28IE0224-HO
REGULATION : FCC15.247(d)/RSS-210A8.5
TEST DISTANCE : 3/1m
DATE : 06/25/2008
TEMPERATURE : 25deg.C
HUMIDITY : 62%
ENGINEER : Takahiro Hatakeda

PK DETECT (RBW: 1MHz, VBW: 1MHz)

No.	FREQ [MHz]	S/A READING		ANT Factor [dB/m]	AMP GAIN [dB]	CABLE LOSS [dB]	Hi-Pass Filter [dB]	RESULT		Limit PK [dBuV/m]	MARGIN	
		HOR	VER					HOR	VER		HOR	VER
Test distance 3meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss												
1	4882.0	45.7	48.1	31.3	30.6	4.1	0.8	51.3	53.7	73.9	22.6	20.2
2	7323.0	41.3	42.8	35.8	31.4	4.6	0.7	51.0	52.5	73.9	22.9	21.4
3	9764.0	42.8	42.3	38.4	32.1	5.5	1.2	55.8	55.3	73.9	18.1	18.6
Test distance 1.0meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss - Dfac												
4	12205.0	-	-	-	-	-	-	-	-	-	-	-
5	14646.0	-	-	-	-	-	-	-	-	-	-	-
6	17087.0	-	-	-	-	-	-	-	-	-	-	-
7	19528.0	-	-	-	-	-	-	-	-	-	-	-
8	21969.0	-	-	-	-	-	-	-	-	-	-	-
9	24410.0	44.6	44.9	38.6	30.6	7.7	0.0	50.8	51.1	73.9	23.1	22.8

AV DETECT (RBW: 1MHz, VBW: 270Hz)

No.	FREQ [MHz]	S/A READING		ANT Factor [dB/m]	AMP GAIN [dB]	CABLE LOSS [dB]	Hi-Pass Filter [dB]	RESULT		Limit AV [dBuV/m]	MARGIN	
		HOR	VER					HOR	VER		HOR	VER
Test distance 3meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss												
1	4882.0	36.8	40.3	31.3	30.6	4.1	0.8	42.4	45.9	53.9	11.5	8.0
2	7323.0	29.1	29.1	35.8	31.4	4.6	0.7	38.8	38.8	53.9	15.1	15.1
3	9764.0	29.1	29.1	38.4	32.1	5.5	1.2	42.1	42.1	53.9	11.8	11.8
Test distance 1.0meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss - Dfac												
4	12205.0	-	-	-	-	-	-	-	-	-	-	-
5	14646.0	-	-	-	-	-	-	-	-	-	-	-
6	17087.0	-	-	-	-	-	-	-	-	-	-	-
7	19528.0	-	-	-	-	-	-	-	-	-	-	-
8	21969.0	-	-	-	-	-	-	-	-	-	-	-
9	24410.0	31.9	32.0	38.6	30.6	7.7	0.0	38.1	38.2	53.9	15.8	15.7

Test Distance 1.0m : Distance Factor(Dfac) = 20log(3/1) = 9.5dB

*Except for the above table : All other spurious emissions were less than 20dB for the limit.

*In the frequency over the 3rd harmonic, the noise from the EUT was not seen.The data above is its base noise.

*The test result is round off to one or two decimal places, so some differences might be observed.

*Hi-Pass Fiter was not used for factor 0.0dB of the above table.

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Radiated Spurious Emission (above 1GHz)
Tx, Ch:High (DH5)

UL Japan, Inc.
Head Office EMC Lab. No.3Semi Anechoic Chamber

Company : Sharp Corporation
Equipment : Cellular Phone
Model No. : WX-T825
Sample No. : 004401/11/135069/6
Power : AC 120V/60Hz
Mode : BT Tx DH5 2480MHz
Remarks : Hor Y , Ver Z-axis

REPORT NO : 28IE0224-HO
REGULATION : FCC15.247(d)/RSS-210A8.5
TEST DISTANCE : 3/1m
DATE : 06/25/2008
TEMPERATURE : 25deg.C
HUMIDITY : 62%
ENGINEER : Takahiro Hatakeda

PK DETECT (RBW: 1MHz, VBW: 1MHz)

No.	FREQ [MHz]	S/A READING		ANT Factor [dB/m]	AMP GAIN [dB]	CABLE LOSS [dB]	Hi-Pass Filter [dB]	RESULT		Limit PK [dBuV/m]	MARGIN	
		HOR	VER					HOR	VER		HOR	VER
Test distance 3meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss												
1	2483.5	52.8	51.6	26.9	32.8	2.7	0.0	49.6	48.4	73.9	24.3	25.5
2	4960.0	46.7	48.5	31.5	30.6	4.1	0.8	52.5	54.3	73.9	21.4	19.6
3	7440.0	42.3	42.0	36.0	31.4	4.7	0.7	52.3	52.0	73.9	21.6	21.9
4	9920.0	41.8	42.3	38.5	32.2	5.5	1.2	54.8	55.3	73.9	19.1	18.6
Test distance 1.0meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss - Dfac												
5	12400.0	-	-	-	-	-	-	-	-	-	-	-
6	14880.0	-	-	-	-	-	-	-	-	-	-	-
7	17360.0	-	-	-	-	-	-	-	-	-	-	-
8	19840.0	-	-	-	-	-	-	-	-	-	-	-
9	22320.0	-	-	-	-	-	-	-	-	-	-	-
10	24800.0	46.9	46.6	38.9	29.9	7.8	0.0	54.2	53.9	73.9	19.7	20.0

AV DETECT (RBW: 1MHz, VBW: 270Hz)

No.	FREQ [MHz]	S/A READING		ANT Factor [dB/m]	AMP GAIN [dB]	CABLE LOSS [dB]	Hi-Pass Filter [dB]	RESULT		Limit AV [dBuV/m]	MARGIN	
		HOR	VER					HOR	VER		HOR	VER
Test distance 3meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss												
1	2483.5	31.5	32.1	26.9	32.8	2.7	0.0	28.3	28.9	53.9	25.6	25.0
2	4960.0	38.9	41.3	31.5	30.6	4.1	0.8	44.7	47.1	53.9	9.2	6.8
3	7440.0	30.3	29.8	36.0	31.4	4.7	0.7	40.3	39.8	53.9	13.6	14.1
4	9920.0	29.2	29.2	38.5	32.2	5.5	1.2	42.2	42.2	53.9	11.7	11.7
Test distance 1.0meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss - Dfac												
5	12400.0	-	-	-	-	-	-	-	-	-	-	-
6	14880.0	-	-	-	-	-	-	-	-	-	-	-
7	17360.0	-	-	-	-	-	-	-	-	-	-	-
8	19840.0	-	-	-	-	-	-	-	-	-	-	-
9	22320.0	-	-	-	-	-	-	-	-	-	-	-
10	24800.0	33.8	33.8	38.9	29.9	7.8	0.0	41.1	41.1	53.9	12.8	12.8

Test Distance 1.0m : Distance Factor(Dfac) = 20log(3/1) = 9.5dB

*Except for the above table : All other spurious emissions were less than 20dB for the limit.

*In the frequency over the 3rd harmonic, the noise from the EUT was not seen. The data above is its base noise.

*The test result is round off to one or two decimal places, so some differences might be observed.

*Hi-Pass Fiter was not used for factor 0.0dB of the above table.

Radiated Spurious Emission (above 1GHz)
Rx, Ch:Mid

UL Japan, Inc.
Head Office EMC Lab. No.3Semi Anechoic Chamber

Company : Sharp Corporation
Equipment : Cellular Phone
Model No. : WX-T825
Sample No. : 004401/11/135069/6
Power : AC 120V/60Hz
Mode : BT Rx 2441MHz
Remarks : Hor Y , Ver Z-axis

REPORT NO : 28IE0224-HO
REGULATION : FCC15.247(d)/RSS-210A8.5
TEST DISTANCE : 3m
DATE : 06/25/2008
TEMPERATURE : 25deg.C
HUMIDITY : 62%
ENGINEER : Takahiro Hatakeda

PK DETECT (RBW: 1MHz, VBW: 1MHz)

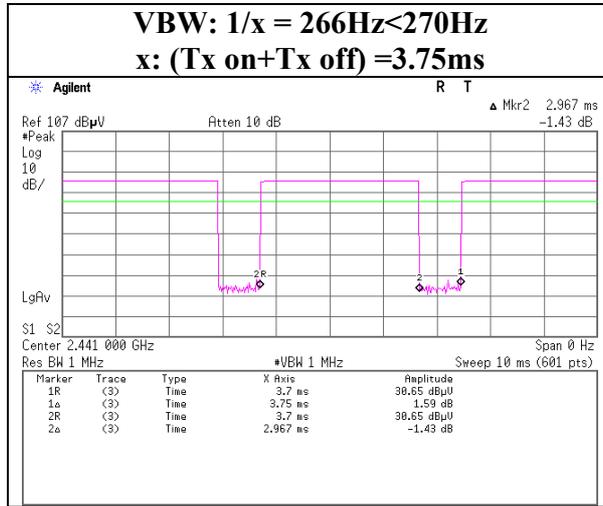
No.	FREQ [MHz]	S/A READING		ANT Factor [dB/m]	AMP GAIN [dB]	CABLE LOSS [dB]	Hi-Pass Filter [dB]	RESULT		Limit PK [dBuV/m]	MARGIN	
		HOR	VER					HOR	VER		HOR	VER
Test distance 3meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss												
1	2441.0	41.8	42.1	26.8	32.8	2.7	0.0	38.5	38.8	73.9	35.4	35.1

AV DETECT (RBW: 1MHz, VBW: 10Hz)

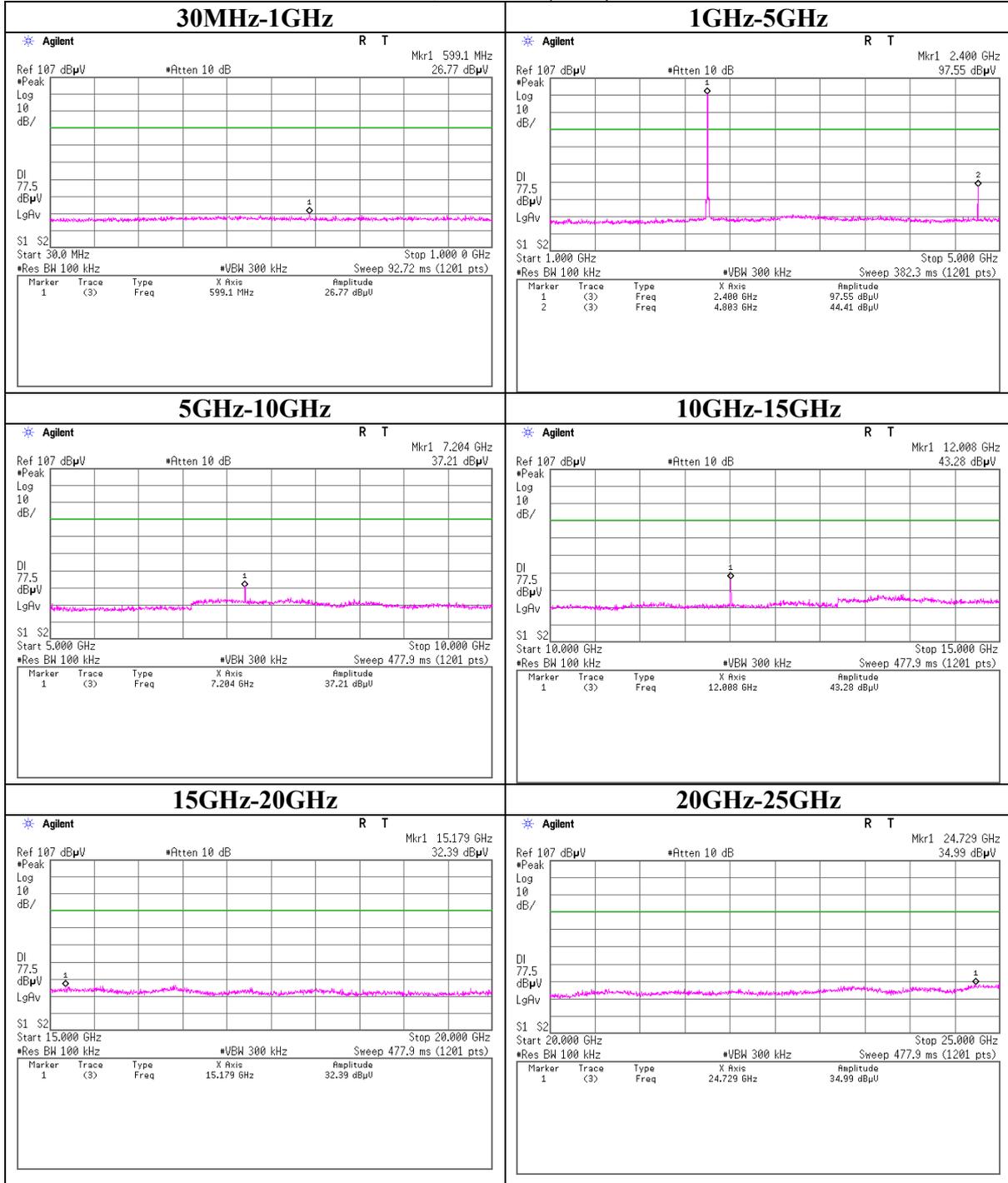
No.	FREQ [MHz]	S/A READING		ANT Factor [dB/m]	AMP GAIN [dB]	CABLE LOSS [dB]	Hi-Pass Filter [dB]	RESULT		Limit AV [dBuV/m]	MARGIN	
		HOR	VER					HOR	VER		HOR	VER
Test distance 3meters RESULT=Reading + ANT Factor - Amp Gain + Cable Loss + Filter Loss												
1	2441.0	28.3	28.3	26.8	32.8	2.7	0.0	25.0	25.0	53.9	28.9	28.9

*Except for the above table : All other spurious emissions were less than 20dB for the limit.
*The test result is round off to one or two decimal places, so some differences might be observed.
*Hi-Pass Fiter was not used for factor 0.0dB of the above table.

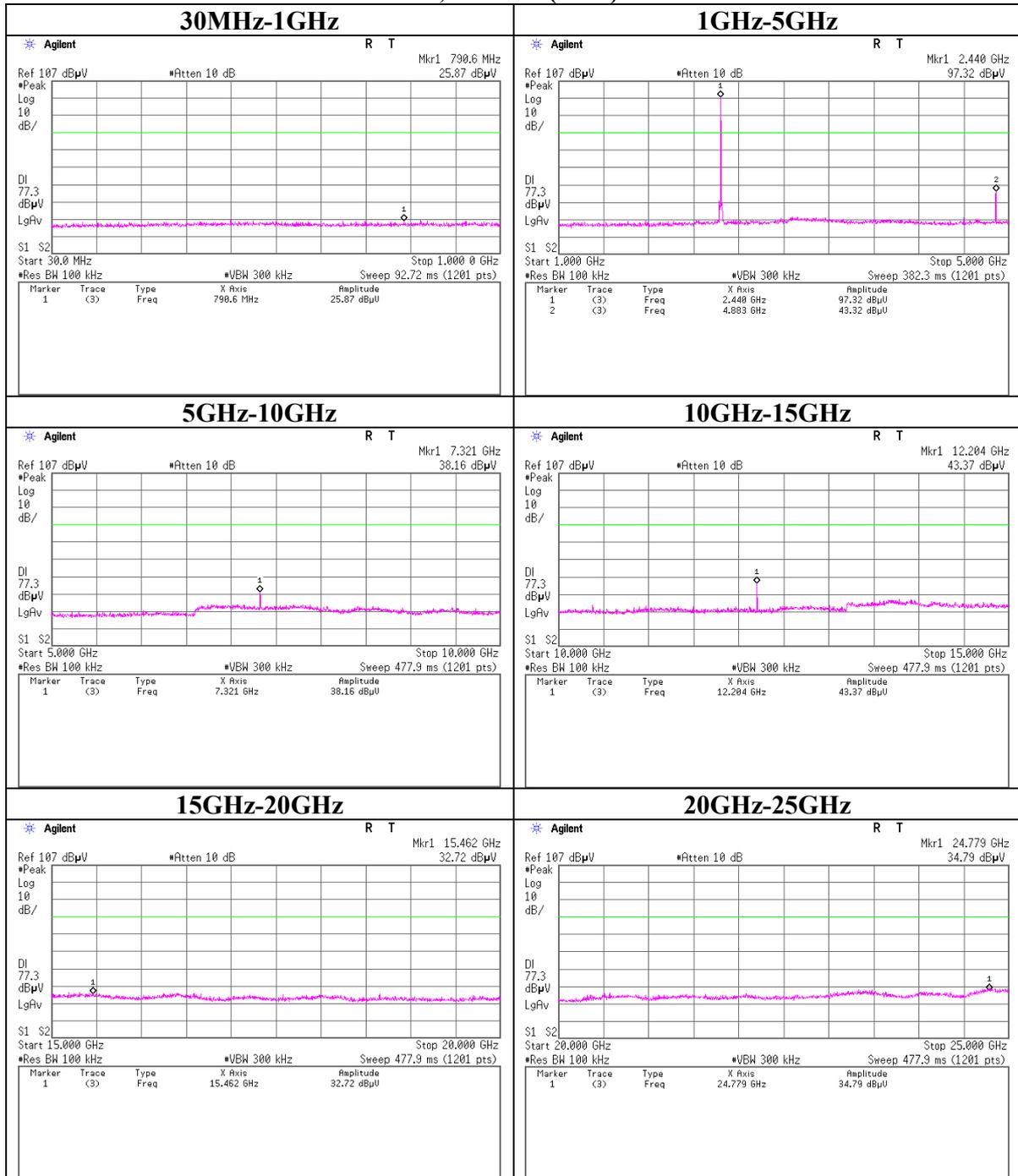
VBW (AV) Calculation



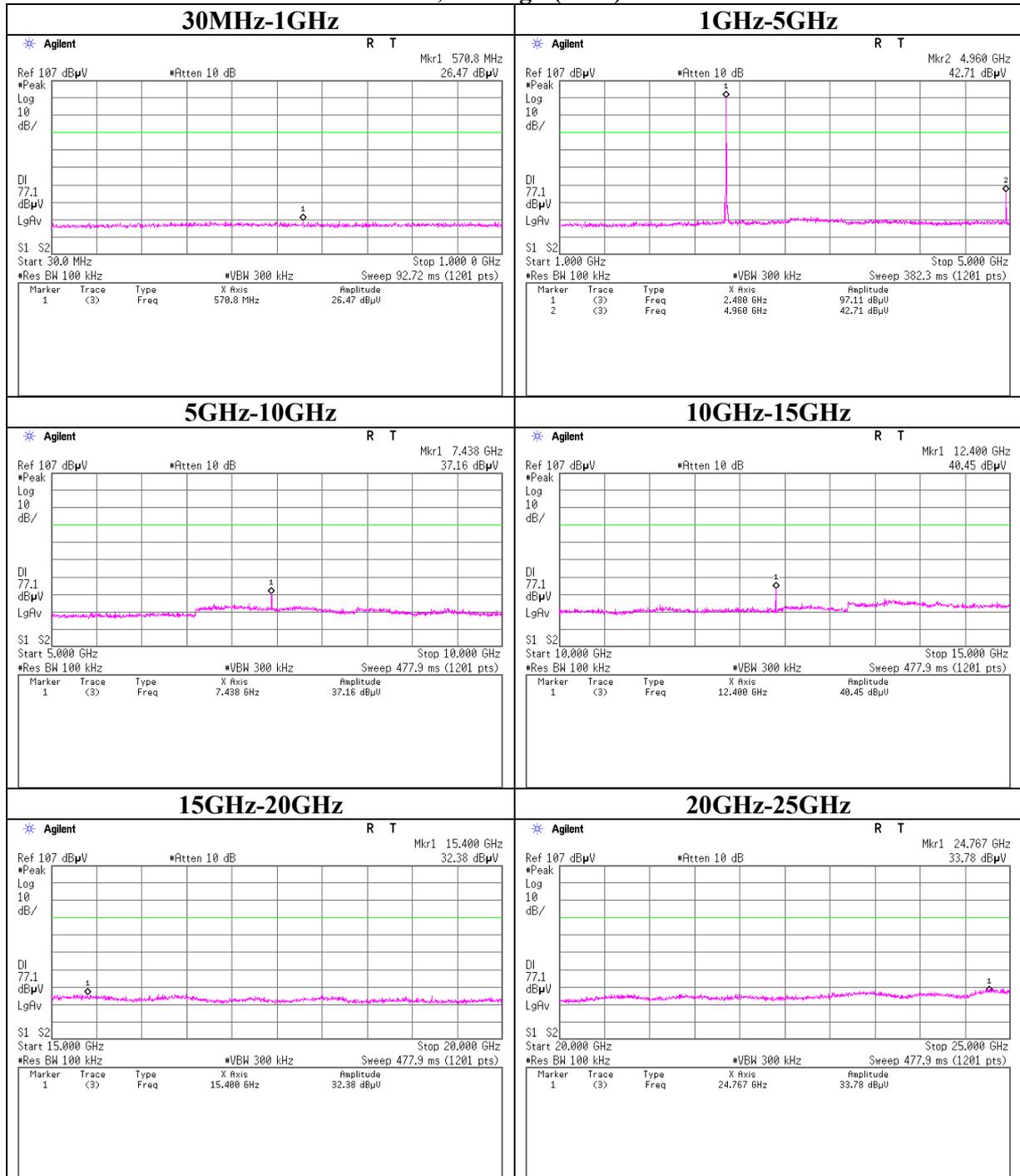
Conducted Spurious Emission
Tx, Ch:Low (DH5)



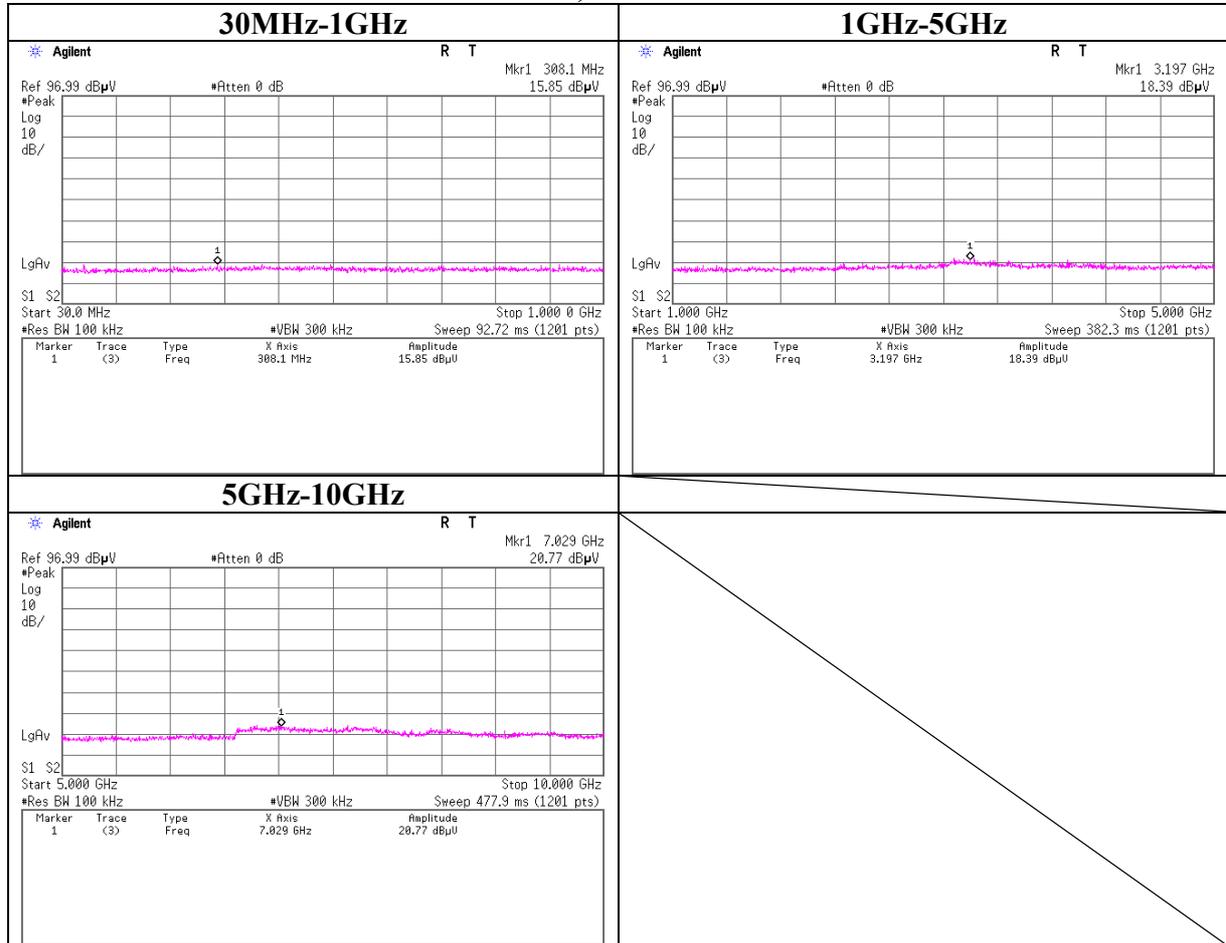
Conducted Spurious Emission
Tx, Ch:Mid (DH5)



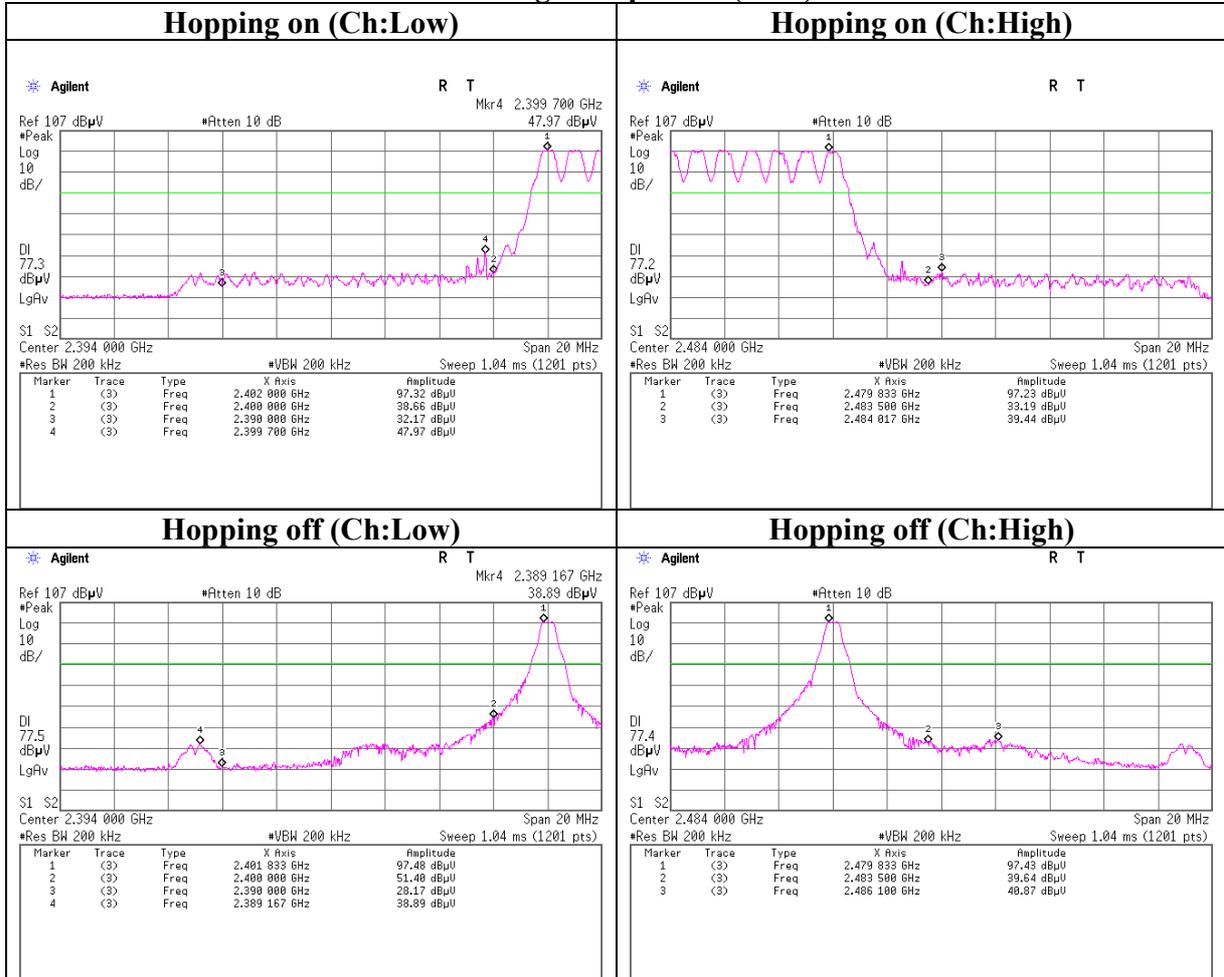
Conducted Spurious Emission
Tx, Ch:High (DH5)



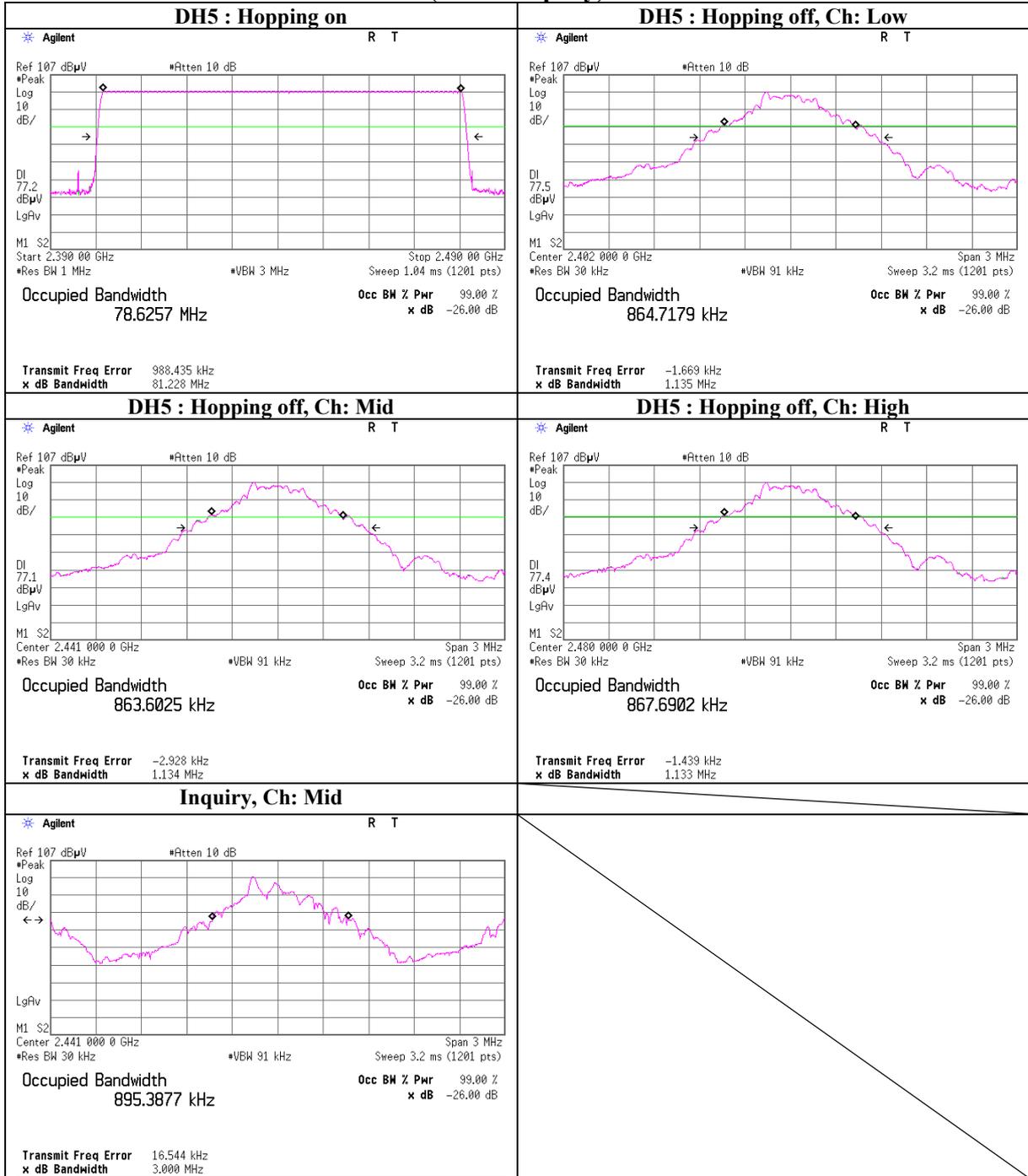
Conducted Spurious Emission
Rx, Ch:Mid



Conducted Spurious Emission
Band Edge compliance (DH5)



99% Occupied Bandwidth
(DH5 / Inquiry)



APPENDIX 3:Test instruments

EMI test equipment

Control No.	Instrument	Manufacturer	Model No	Test Item	Calibration Date * Interval(month)
MAEC-03	Anechoic Chamber	TDK	Semi Anechoic Chamber 3m	CE/RE	2008/03/25 * 12
MOS-13	Thermo-Hygrometer	Custom	CTH-180	CE/RE/AT	2008/01/10 * 12
MJM-06	Measure	PROMART	SEN1955	CE/RE	-
MSTW-14	EMI measurement program	TSJ	TEPTO-DV	CE/RE	-
MSA-10	Spectrum Analyzer	Agilent	E4448A	CE/RE	2008/02/27 * 12
MHA-20	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	RE	2008/04/23 * 12
MCC-56	Microwave Cable 1G-26.5GHz	Suhner	SUCOFLEX104	RE	2008/03/12 * 12
MPA-11	MicroWave System Amplifier	Agilent	83017A	RE	2008/03/13 * 12
MHA-16	Horn Antenna 15-40GHz	Schwarzbeck	BBHA9170	RE	2008/04/30 * 12
MHF-19	High Pass Filter 3.5-18.0GHz	TOKIMEC	TF323DCA	RE	2007/12/10 * 12
MCC-78	Microwave Cable 1G-26.5GHz	Suhner	SUCOFLEX104	RE	2007/12/26 * 12
MLS-06	LISN(AMN)	Schwarzbeck	NSLK8127	CE	2008/02/19 * 12
MTR-08	Test Receiver	Rohde & Schwarz	ESCI	RE / CE	2008/06/12 * 12
MCC-51	Coaxial cable	UL Japan	-	RE / CE	2007/07/26 * 12
MBA-03	Biconical Antenna	Schwarzbeck	BBA9106	RE	2008/01/12 * 12
MLA-03	Logperiodic Antenna	Schwarzbeck	USLP9143	RE	2008/01/12 * 12
MAT-30	Attenuator(6dB)	TME	UFA-01	RE	2008/03/10 * 12
MPA-13	Pre Amplifier	SONOMA INSTRUMENT	310	RE	2008/03/06 * 12
MAT-23	Attenuator(10dB) DC-18GHz	Orient Microwave	BX10-0476-00	AT	2008/03/05 * 12
MPM-08	Power Meter	Anritsu	ML2495A	AT	2007/09/12 * 12
MSA-10	Spectrum Analyzer	Agilent	E4448A	AT	2008/02/27 * 12
MCC-67	Microwave Cable 1G-40GHz	Schner	SUCOFLEX102	AT	2008/04/04 * 12
MPSE-11	Power sensor	Anritsu	MA2411B	AT	2007/09/12 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with traceable calibrations. Each calibration is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item: CE: Conducted Emission
RE: Radiated Emission
AT: Antenna Terminal Conducted test

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